



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Walter SCHWARZENBACH et al.

Confirmation No.

Application No.:

Group Art Unit:

Filing Date:

Examiner:

For: METHOD OF MAKING CAVITIES IN A
SEMICONDUCTOR WAFER

Atty. Docket No.: 4717-9200

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

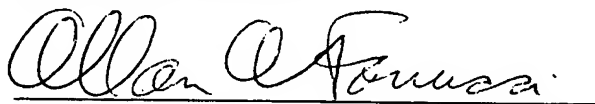
Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed are copies of nine (9) references for the Examiner's review and consideration. These references are listed on the enclosed Form PTO-1449.

These references were cited in the European Search Report a copy of which is enclosed. It is respectfully requested that these references be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee or certification is believed to be due for this submission since the references are being submitted concurrent with the filing of this application. Should any fees be required, however, please charge such fees to **Winston & Strawn** Deposit Account No. 50-1814.

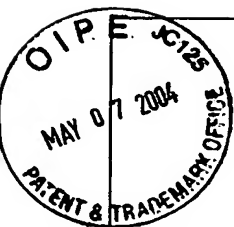
Date: 12/12/03

Respectfully submitted,


Allan A. Fanucci (Reg. No. 30,256)

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Enclosures



LIST OF REFERENCES CITED BY APPLICANT
(Use several sheets if necessary)

ATTY. DOCKET NO.:

4717-9200

APPLICATION NO.:

APPLICANT:

Walter SCHWARZENBACH et al.

FILING DATE:

GROUP:

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	4,956,314	9/1990	Tam et al.	437	241	
	AB	5,576,250	11/1996	Diem et al.	437	228	
	AC	5,780,885	7/1998	Diem et al.	257	254	
	AD	5,976,945	11/1999	Chi et al.	438	386	
	AE	6,171,923 B1	1/2001	Chi et al.	438	386	
	AF	6,335,292 B1	1/2002	Li et al.	438	714	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AG	2 700 065 (with English Abstract)	7/1994	France			X	
	AH	2 795 554 (with English Abstract)	12/2000	France			X	
	AI	JP 06132262 (with English Abstract)	5/1994	Japan			X	
	AJ							
	AK							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AL	
	AM	
	AN	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

9202

**ANNEXE AU RAPPORT DE RECHERCHE PRÉLIMINAIRE
RELATIF A LA DEMANDE DE BREVET FRANÇAIS NO. FR 0216409 FA 629144**

La présente annexe indique les membres de la famille de brevets relatifs aux documents brevets cités dans le rapport de recherche préliminaire visé ci-dessus.
Les dits membres sont contenus au fichier informatique de l'Office européen des brevets à la date du 02-09-2003
Les renseignements fournis sont donnés à titre indicatif et n'engagent pas la responsabilité de l'Office européen des brevets, ni de l'Administration française

Document brevet cité au rapport de recherche		Date de publication		Membre(s) de la famille de brevet(s)	Date de publication
✓ FR 2700065	A	01-07-1994	FR	2700065 A1	01-07-1994
			DE	69318956 D1	09-07-1998
			DE	69318956 T2	17-12-1998
			EP	0605300 A1	06-07-1994
			JP	3226402 B2	05-11-2001
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✓ US 4956314	A	11-09-1990	JP	3006820 A	14-01-1991
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✓ FR 2795554	A	29-12-2000	FR	2795554 A1	29-12-2000
			EP	1192653 A1	03-04-2002
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